

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/511,402 SPIESS ET AL.	
		Examiner	Art Unit	Page 1 of 1 Mahmoud Dahimene

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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	U	Haoying Li et al. (Journal of Nanoparticle Research, 3 (2001), pp. 157-160)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.